

Product Overview

The MSCSMG120ANPCM11TPAG device is an ANPC 1200V, Silicon Carbide (SiC) power module. The following figures show the electrical diagram and pinout location of the device.

Figure 1. Electrical Diagram

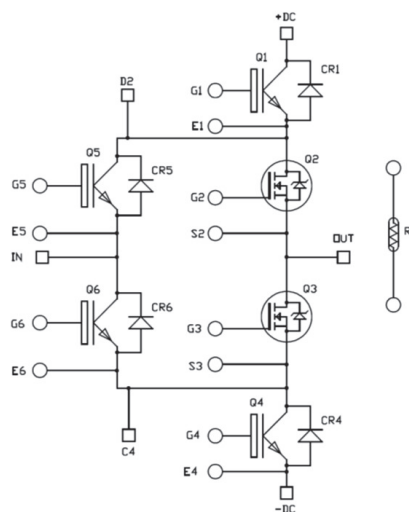
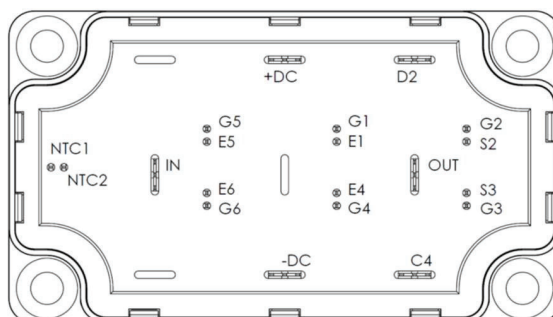


Figure 2. Pinout Location



Note: All ratings are at $T_j = 25\text{ }^{\circ}\text{C}$, unless otherwise specified.



These devices are sensitive to electrostatic discharge. Proper handling procedures must be followed.

Features

The MSCSMG120ANPCM11TPAG device has the following key features:

- SiC Power MOSFET
 - Low $R_{DS(on)}$
 - High temperature performance
- IGBT7
 - Low voltage drop
 - Low leakage current
- Low stray inductance
- Internal thermistor for temperature monitoring
- AlN substrate for improved thermal performance
- Copper baseplate

Benefits

The MSCSMG120ANPCM11TPAG device has the following benefits:

- High power and efficiency converters and inverters
- Direct mounting to heat sink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

Application

The MSCSMG120ANPCM11TPAG device has the following applications:

- AC/DC converter (ANPC hybrid configuration)

1. Electrical Specifications

The following sections show the electrical specifications of the MSCSMG120ANPCM11TPAG device.

1.1. SiC MOSFET Characteristics (per SiC MOSFET)

The following table lists the absolute maximum ratings of the MSCSMG120ANPCM11TPAG device.

Table 1-1. Absolute Maximum Ratings

Symbol	Parameter	Maximum Ratings	Unit
V_{DS}	Drain-source voltage	1200	V
I_D	Continuous drain current	$T_C = 25\text{ }^{\circ}\text{C}$	A
		$T_C = 80\text{ }^{\circ}\text{C}$	
I_{DM}	Pulsed drain current	500	
V_{GS}	Gate-source voltage	-10/23	V
$R_{DS(on)}$	Drain-source ON resistance	10.4	m Ω
P_D	Power dissipation	$T_C = 25\text{ }^{\circ}\text{C}$	W

The following table lists the electrical characteristics of the MSCSMG120ANPCM11TPAG device.

Table 1-2. Electrical Characteristics

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0\text{V}; V_{DS} = 1200\text{V}$	—	30	300	μA
$R_{DS(on)}$	Drain-source ON resistance	$V_{GS} = 20\text{V}$ $I_D = 120\text{A}$	$T_J = 25^{\circ}\text{C}$	8.4	10.4	m Ω
			$T_J = 175^{\circ}\text{C}$	13.4	—	
$V_{GS(th)}$	Gate threshold voltage	$V_{GS} = V_{DS}; I_D = 9\text{ mA}$	1.8	2.8	—	V
I_{GSS}	Gate-source leakage current	$V_{GS} = 20\text{V}; V_{DS} = 0\text{V}$	—	—	300	nA

The following table lists the dynamic characteristics of the MSCSMG120ANPCM11TPAG device.

Table 1-3. Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{GS} = 0\text{V}$	—	9060	—	pF
C_{oss}	Output capacitance	$V_{DS} = 1000\text{V}$	—	810	—	
C_{rss}	Reverse transfer capacitance	$f = 1\text{ MHz}$	—	75	—	
Q_g	Total gate charge	$V_{GS} = -5/20\text{V}$	—	696	—	nC
Q_{gs}	Gate-source charge	$V_{Bus} = 800\text{V}$	—	123	—	
Q_{gd}	Gate-drain charge	$I_D = 120\text{A}$	—	150	—	
$t_{d(on)}$	Turn-on delay time	$V_{GS} = -5/20\text{V}$	—	30	—	ns
t_r	Rise time	$V_{Bus} = 600\text{V}$	—	30	—	
$t_{d(off)}$	Turn-off delay time	$I_D = 150\text{A}$	—	50	—	
t_f	Fall time	$R_{Gon} = 2.7\Omega; R_{Goff} = 1.6\Omega$	—	25	—	
E_{on}	Turn-on energy	$V_{GS} = -5/+20\text{V}$ $V_{Bus} = 600\text{V}$	$T_J = 150^{\circ}\text{C}$	3.6	—	mJ
E_{off}	Turn-off energy	$I_D = 150\text{A}$ $R_{Gon} = 2.7\Omega$ $R_{Goff} = 1.6\Omega$	$T_J = 150^{\circ}\text{C}$	2	—	
R_{Gint}	Internal gate resistance		—	2	—	Ω
R_{thJC}	Junction-to-case thermal resistance		—	—	0.144	$^{\circ}\text{C/W}$

The following table lists the body diode ratings and characteristics (per SiC MOSFET) of the MSCSMG120ANPCM11TPAG device.

Table 1-4. Body Diode Ratings and Characteristics

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
V_{SD}	Body diode forward voltage	$V_{GS} = 0V$; $I_{SD} = 120A$	—	4	—	V
		$V_{GS} = -5V$; $I_{SD} = 120A$	—	4.2	—	
t_{rr}	Reverse recovery time	$I_{SD} = 120A$; $V_{GS} = -5V$ $V_R = 800V$; $di_F/dt = 3000 A/\mu s$	—	90	—	ns
Q_{rr}	Reverse recovery charge		—	1650	—	nC
I_{rr}	Reverse recovery current		—	40.5	—	A

1.2. IGBT7 and Si Diode Parameters (per IGBT and diode)

The following table lists the absolute maximum ratings of the MSCSMG120ANPCM11TPAG device.

Table 1-5. Absolute Maximum Ratings

Symbol	Parameter		Maximum Ratings	Unit
V _{CES}	Collector-emitter voltage		1200	V
I _C	Continuous collector current	T _C = 25°C	260	A
		T _C = 115°C	150	
I _{CM}	Pulsed collector current, t _p limited by T _J max		300	
V _{GE}	Gate-emitter voltage		±20	V
	Transient gate-emitter voltage		±25	
P _D	Power dissipation	T _C = 25 °C	777	W

The following table lists the electrical characteristics of the MSCSMG120ANPCM11TPAG device.

Table 1-6. Electrical Characteristics

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
I_{CES}	Zero gate voltage collector current	$V_{GE} = 0V$; $V_{CE} = 1200V$	—	—	12	μA
$V_{CE(sat)}$	Collector emitter saturation voltage	$V_{GE} = 15V$ $I_C = 150A$	$T_J = 25^\circ C$	1.55	1.8	V
			$T_J = 125^\circ C$	1.7	—	
			$T_J = 175^\circ C$	1.77	—	
$V_{GE(th)}$	Gate threshold voltage	$V_{GE} = V_{CE}$; $I_C = 3.5 mA$	5.15	5.8	6.45	V
I_{GES}	Gate-emitter leakage current	$V_{GE} = 20V$; $V_{CE} = 0V$	—	—	150	nA

The following table lists the dynamic characteristics (per IGBT) of the MSCSMG120ANPCM11TPAG device.

Table 1-7. Dynamic Characteristics

Symbol	Characteristic	Test Conditions		Min.	Typ.	Max.	Unit
C _{ies}	Input capacitance	V _{GE} = 0V V _{CE} = 25V f = 100 kHz		—	30	—	nF
C _{oes}	Output capacitance			—	0.38	—	
C _{res}	Reverse transfer capacitance			—	0.11	—	
Q _G	Gate charge	V _{GE} = ±15V; V _{CE} = 600V; I _C = 150A		—	2.5	—	μC
t _{d(on)}	Turn-on delay time	V _{GS} = ±15V V _{BUS} = 600V I _C = 150A R _G = 3.3Ω	T _J = 25°C	—	172	—	ns
			T _J = 125°C	—	183	—	
			T _J = 175°C	—	189	—	
t _r	Rise time		T _J = 25°C	—	72	—	
			T _J = 125°C	—	77	—	
			T _J = 175°C	—	80	—	
t _{d(off)}	Turn-off delay time		T _J = 25°C	—	331	—	
			T _J = 125°C	—	414	—	
			T _J = 175°C	—	433	—	
t _f	Fall time		T _J = 25°C	—	103	—	
			T _J = 125°C	—	198	—	
			T _J = 175°C	—	262	—	
E _{on}	Turn-on energy	V _{GE} = ±15V V _{BUS} = 600V I _C = 150A R _G = 3.3Ω di/dt = 1700 A/μs dv/dt = 3200 V/μs	T _J = 25°C	—	16.6	—	mJ
			T _J = 125°C	—	24.9	—	
			T _J = 175°C	—	29.6	—	
E _{off}	Turn-off energy		T _J = 25°C	—	10.4	—	
			T _J = 125°C	—	15.9	—	
			T _J = 175°C	—	19.9	—	
R _{Gint}	Internal gate resistance			—	1	—	Ω
I _{sc}	Short circuit data	V _{GE} ≤15V ; V _{BUS} = 800V ; t _p ≤ 8 μs ; T _J = 150°C		—	520	—	A
		V _{GE} ≤15V ; V _{BUS} = 800V ; t _p ≤ 7 μs ; T _J = 175°C		—	490	—	
R _{thJC}	Junction-to-case thermal resistance			—	—	0.193	°C/W

The following table lists the diode ratings and characteristics of the MSCSMG120ANPCM11TPAG device.

Table 1-8. Diode Ratings and Characteristics

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
V_{RRM}	Peak repetitive reverse voltage		—	—	1200	V
I_{RM}	Reverse leakage current	$V_R = 1200\text{ V}$	—	—	8	μA
I_{FRM}	Repetitive forward current, t_p limited by T_{Jmax}		—	—	300	A
I^2t	I^2t value	$t_p = 10\text{ ms}$ $V_R = 0\text{ V}$	$T_J = 125^\circ\text{C}$	—	2700	A^2s
			$T_J = 175^\circ\text{C}$	—	2250	
I_F	DC forward voltage	$T_C = 90^\circ\text{C}$	$T_J = 175^\circ\text{C}$	—	150	A
V_F	Diode forward voltage	$I_F = 150\text{ A}$ $V_{GE} = 0\text{ V}$	$T_J = 25^\circ\text{C}$	—	1.75	V
			$T_J = 125^\circ\text{C}$	—	1.6	
			$T_J = 175^\circ\text{C}$	—	1.52	
I_{rrm}	Reverse recovery current	$V_{GE} = -15\text{ V}$ $I_F = 150\text{ A}$ $V_R = 600\text{ V}$ $di/dt = 1700\text{ A}/\mu\text{s}$	$T_J = 25^\circ\text{C}$	—	65	A
			$T_J = 125^\circ\text{C}$	—	92	
			$T_J = 175^\circ\text{C}$	—	107	
Q_{rr}	Reverse recovery charge	$V_{GE} = -15\text{ V}$ $I_F = 150\text{ A}$ $V_R = 600\text{ V}$ $di/dt = 1700\text{ A}/\mu\text{s}$	$T_J = 25^\circ\text{C}$	—	10.3	μC
			$T_J = 125^\circ\text{C}$	—	21.7	
E_{rr}	Reverse recovery energy	$V_{GE} = -15\text{ V}$ $I_F = 150\text{ A}$ $V_R = 600\text{ V}$ $di/dt = 1700\text{ A}/\mu\text{s}$	$T_J = 25^\circ\text{C}$	—	3.3	mJ
			$T_J = 125^\circ\text{C}$	—	7.3	
R_{thJC}	Junction-to-case thermal resistance		$T_J = 175^\circ\text{C}$	—	9.9	$^\circ\text{C}/\text{W}$
				—	0.318	

1.3. Package and Temperature Sensor Characteristics

The following table lists the thermal and package characteristics of the MSCSMG120ANPCM11TPAG device.

Table 1-9. Thermal and Package Characteristics

Symbol	Characteristic	Min.	Max.	Unit
V_{ISOL}	RMS isolation voltage, any terminal-to-case $t = 1\text{ min}$, 50/60 Hz	4000	—	V
T_J	Operating junction temperature range	SiC MOSFET	—40	175
		IGBT & diode	—40	150
T_{JOP}	Recommended junction temperature under switching conditions	—40	$T_{Jmax} - 25$	$^\circ\text{C}$
T_{STG}	Storage temperature range	—40	125	
T_C	Operating case temperature	—40	125	
τ_M	Mounting torque	To heat sink	M6	N.m
Wt	Package weight	—	250	g

The following table lists the temperature sensor characteristics of the MSCSMG120ANPCM11TPAG device.

Table 1-10. Temperature Sensor Characteristics

Symbol	Characteristic	Min.	Typ.	Max.	Unit
R_{25}	Resistance @ 25°C	—	50	—	$\text{k}\Omega$
$\Delta R_{25}/R_{25}$		—	5	—	%
$B_{25/85}$	$T_{25} = 298.15\text{ K}$	—	3952	—	K
$\Delta B/B$	$T_C = 100^\circ\text{C}$	—	4	—	%

Note:

$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$

Where

- T: Thermistor temperature
- R_T : Thermistor value at T

Note: For more information, see the latest application note on NTC temperature sensor, available on the Microchip website.

1.4. Typical SiC MOSFET Performance Curve

This section shows the typical SiC MOSFET performance curves of the MSCSMG120ANPCM11TPAG device.

Figure 1-1. Output Characteristics, $T_J = 25^\circ\text{C}$

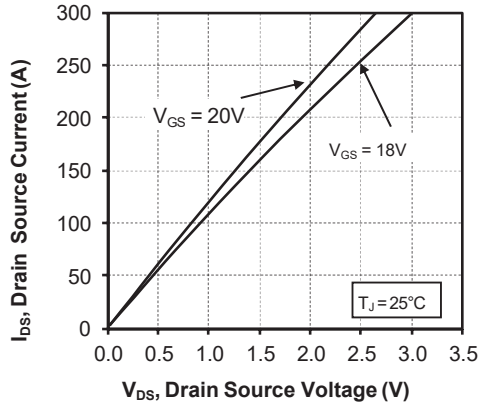


Figure 1-2. Output Characteristics, $T_J = 175^\circ\text{C}$

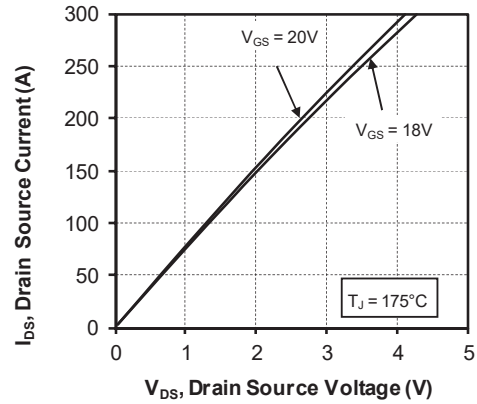


Figure 1-3. Normalized $R_{DS(on)}$ vs. Temperature

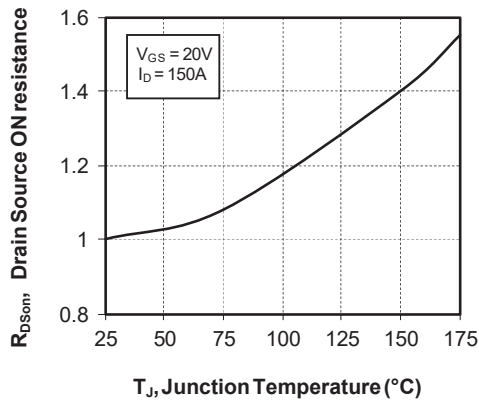


Figure 1-4. Transfer Characteristics

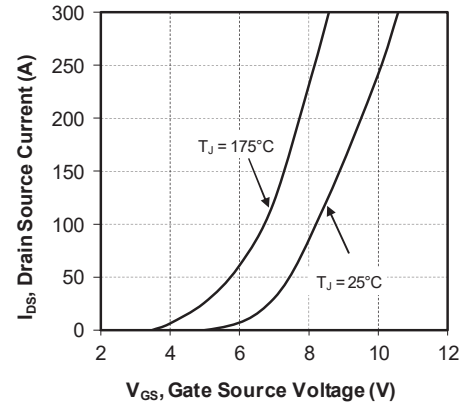


Figure 1-5. Switching Energy vs. R_G

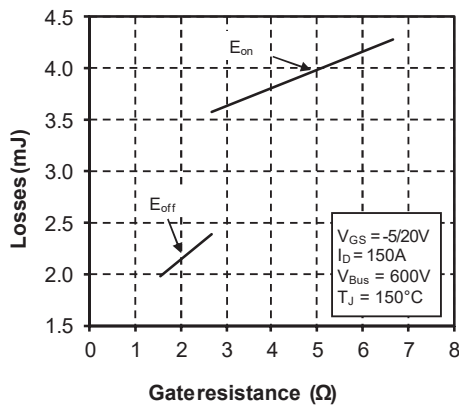


Figure 1-6. Switching Energy vs. Current

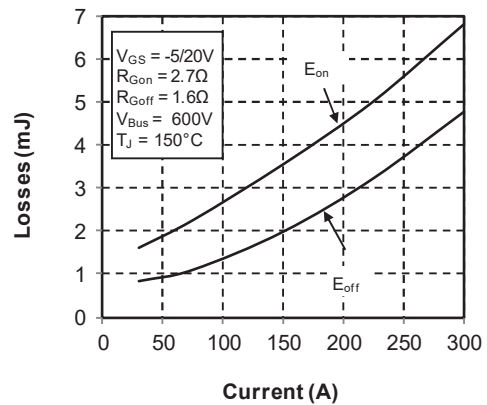


Figure 1-7. Maximum Thermal Impedance

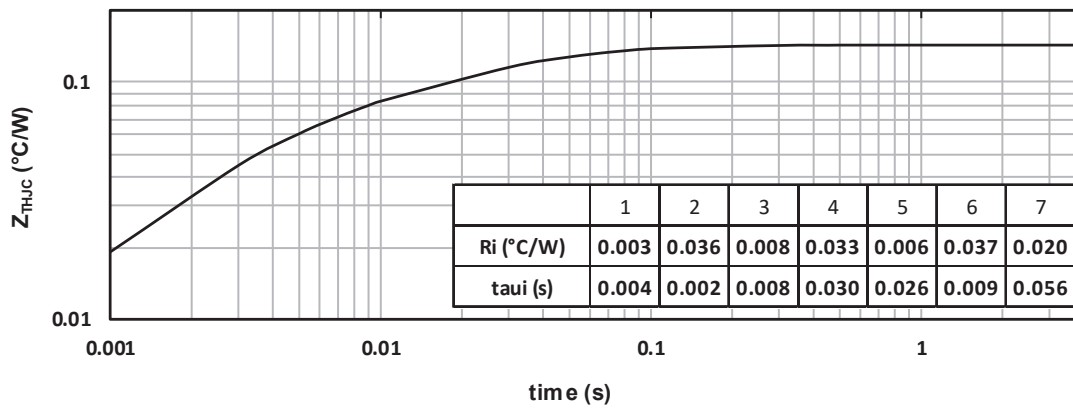


Figure 1-8. Capacitance vs. Drain Source Voltage

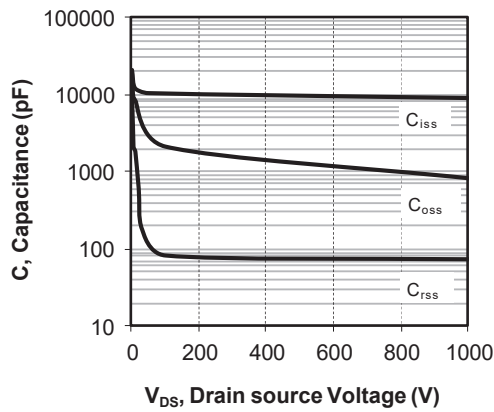


Figure 1-9. Gate Charge vs. Gate Source Voltage

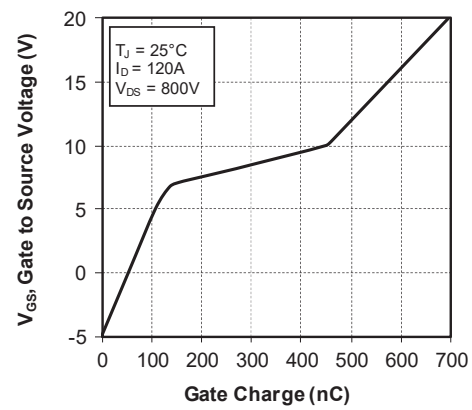


Figure 1-10. Body Diode Characteristics, $T_J = 25^\circ\text{C}$

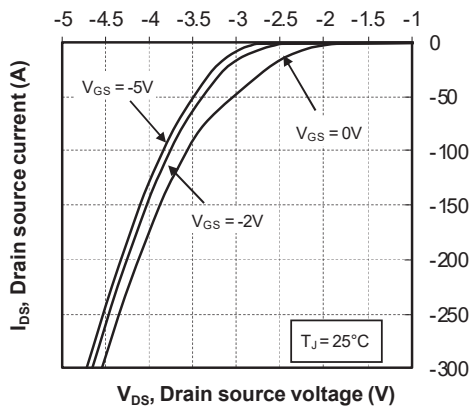


Figure 1-11. 3rd Quadrant Characteristics, $T_J = 25^\circ\text{C}$

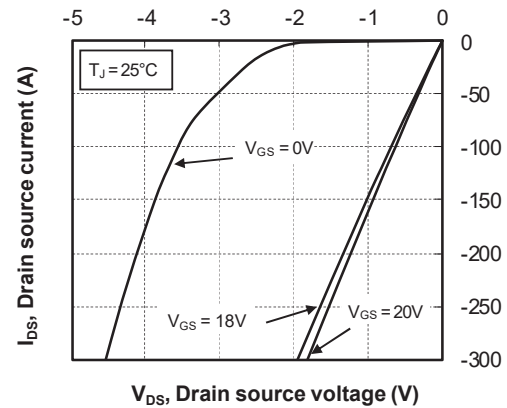


Figure 1-12. Body Diode Characteristics, $T_J = 175^\circ\text{C}$

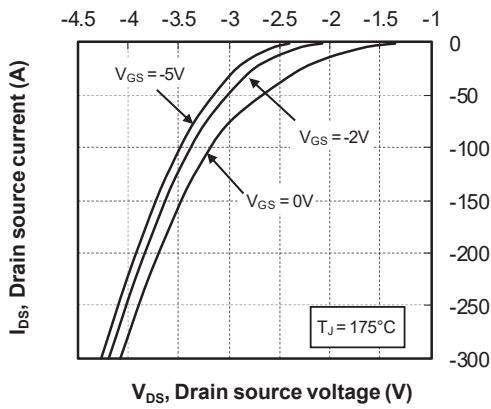


Figure 1-13. 3rd Quadrant Characteristics, $T_J = 175^\circ\text{C}$

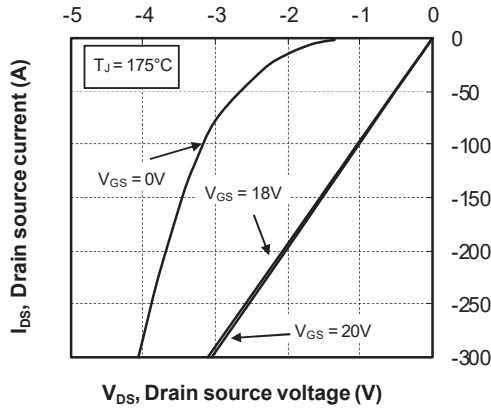
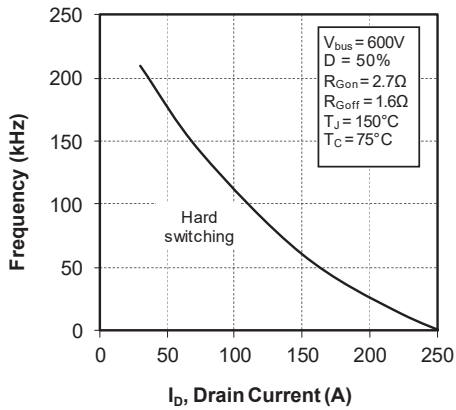


Figure 1-14. Operating Frequency vs. Drain Current



1.5. Typical IGBT and Diode Performance Curve

This section shows the typical IGBT and diode performance curves of the MSCSMG120ANPCM11TPAG device.

Figure 1-15. Output Characteristics

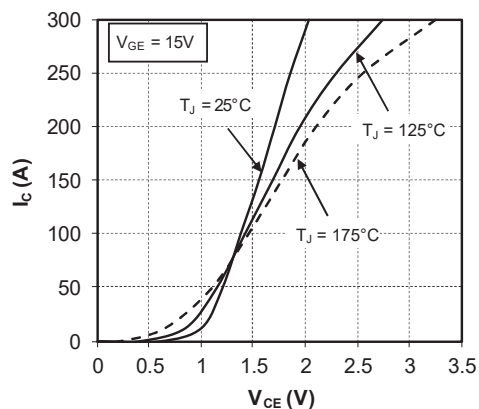


Figure 1-16. Output Characteristics

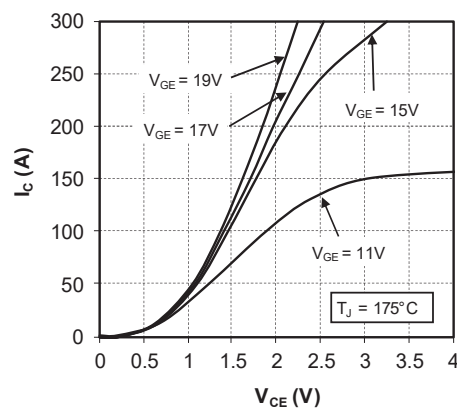


Figure 1-17. Switching Losses vs. Gate Resistance

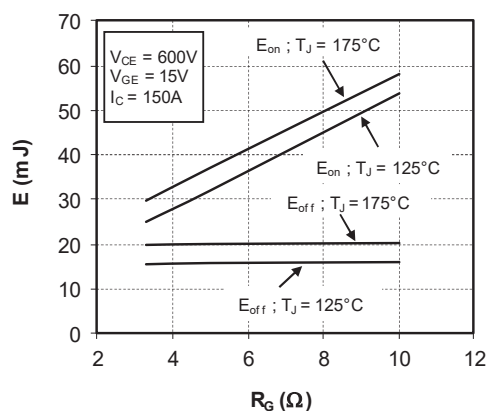


Figure 1-18. Switching Losses vs. Collector Current

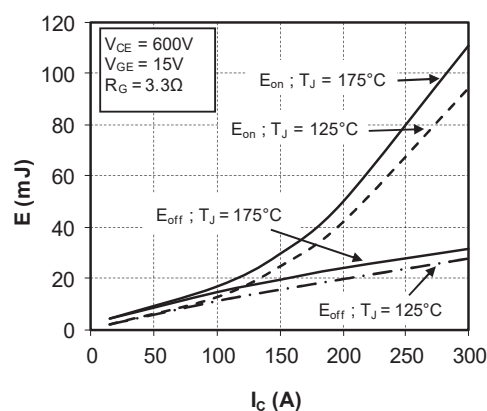


Figure 1-19. Maximum Thermal Impedance

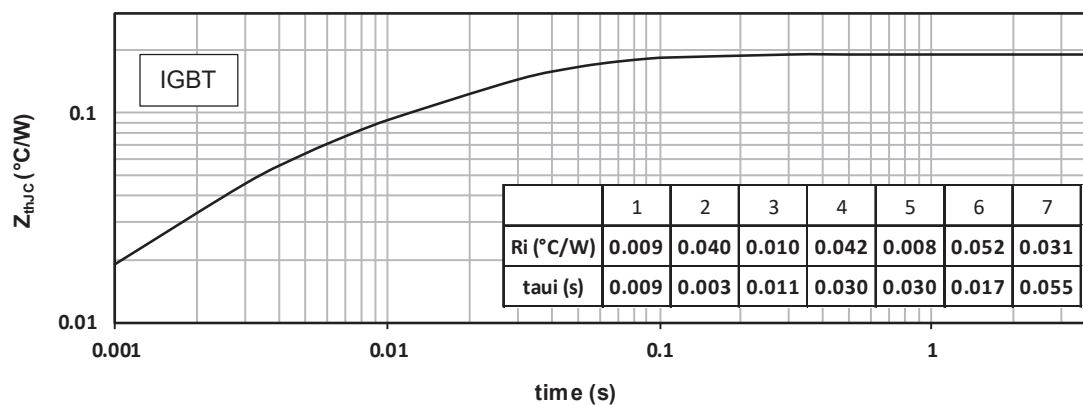


Figure 1-20. Operating Frequency vs. Collector Current

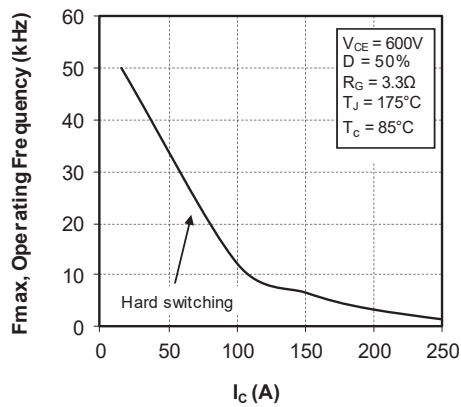


Figure 1-21. Gate Charge vs. Gate Emitter Voltage

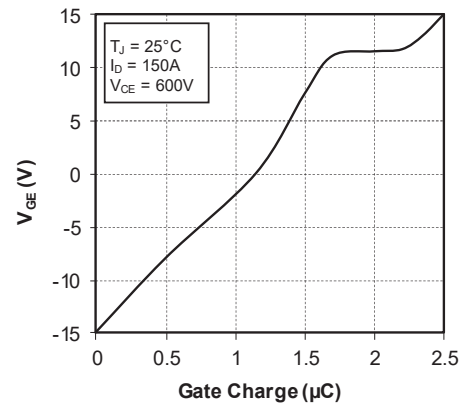


Figure 1-22. Transfer Characteristics

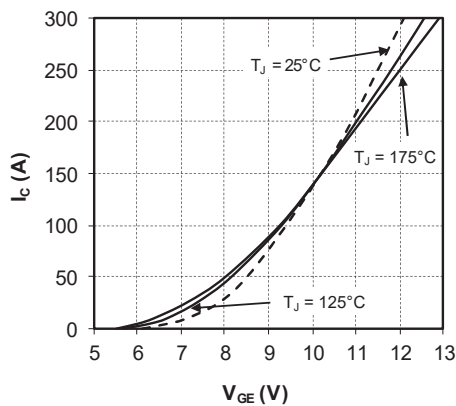


Figure 1-23. Capacity Characteristics

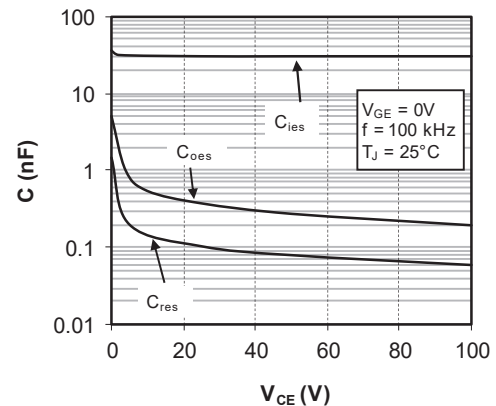


Figure 1-24. Reverse Bias Safe Operating Area

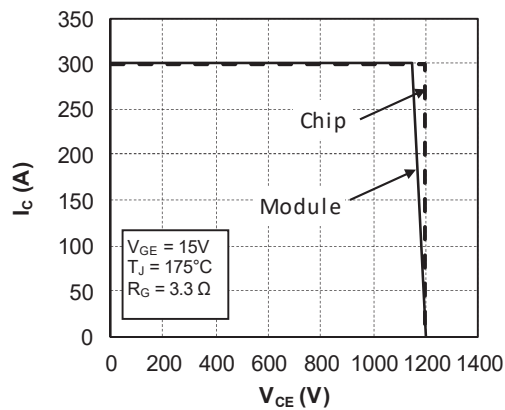


Figure 1-25. Forward Characteristics

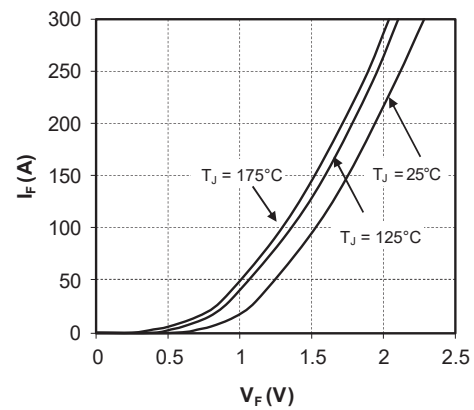


Figure 1-26. Switching Losses vs. Gate Resistance

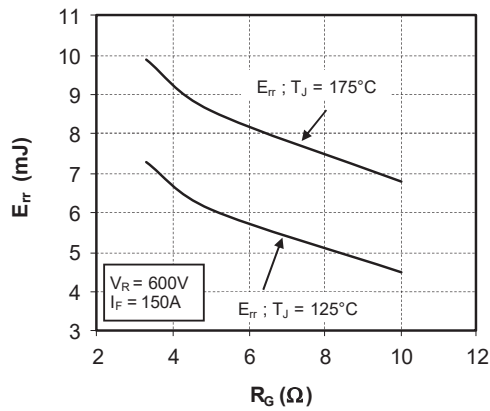


Figure 1-27. Switching Losses vs. Forward Current

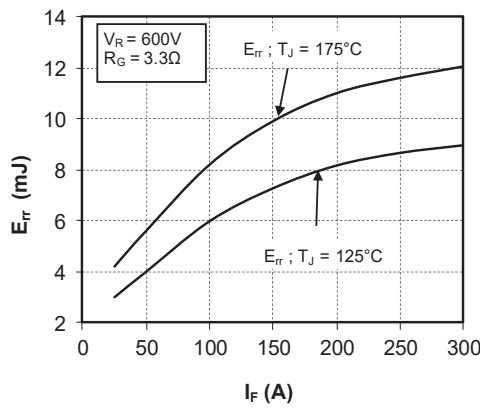
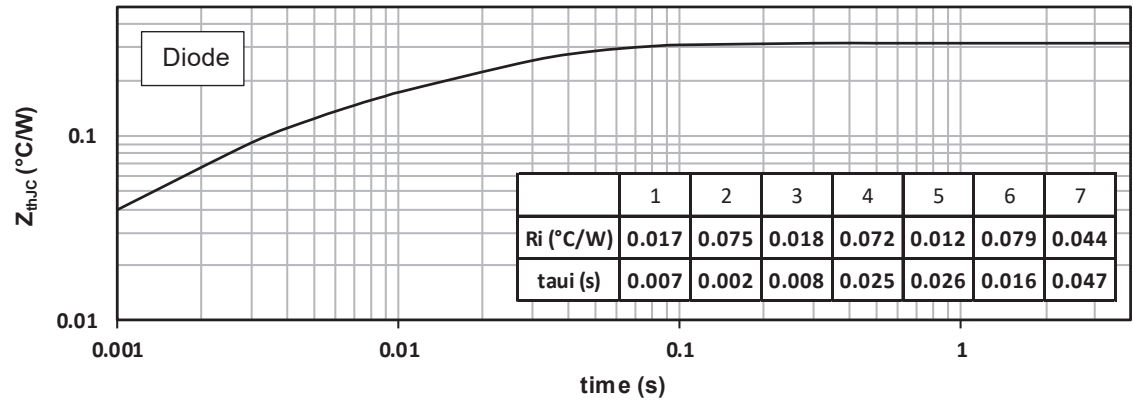


Figure 1-28. Maximum Thermal Impedance



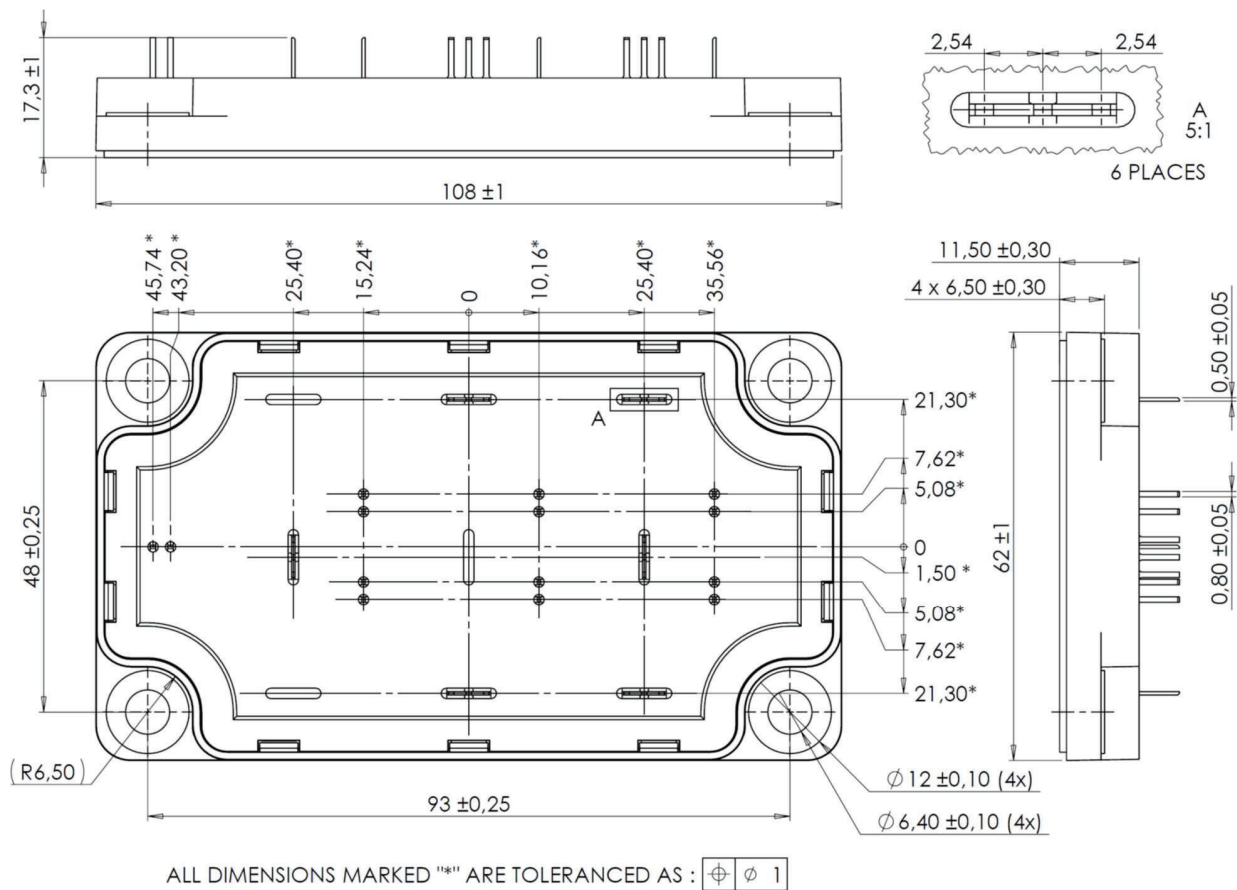
2. Package Specifications

The following section shows the package specification of the MSCSMG120ANPCM11TPAG device.

2.1. Package Outline

The following figure shows the package outline drawing of the MSCSMG120ANPCM11TPAG device. The dimensions in the following figure are in millimeters.

Figure 2-1. Package Outline Drawing



Note: For more information, see the latest application note on mounting instruction for SP6-P power modules, available on the Microchip website.

3. Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

Revision	Date	Description
A	11/2025	Initial Revision

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- Neither Microchip nor any other semiconductor manufacturer can guarantee the security of its code. Code protection does not mean that we are guaranteeing the product is “unbreakable”. Code protection is constantly evolving. Microchip is committed to continuously improving the code protection features of our products.